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ILNAS-EN IEC 62228-6:2022

Integrated circuit - EMC evaluation of transceivers - Part 6: PSI5 transceivers

Integrierte Schaltungen - Bewertung der
elektromagnetischen Verträglichkeit von
Sende-Empfangsgeräten - Teil 6: PSI5-
Transceiver

Circuits intégrés - Évaluation de la CEM
des émetteurs-récepteurs - Partie 6:
Émetteurs-récepteurs PSI5

12/2022



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**Integrated circuit - EMC evaluation of transceivers - Part 6: PSI5
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(IEC 62228-6:2022)**

Circuits intégrés - Évaluation de la CEM des émetteurs-
récepteurs - Partie 6: Émetteurs-récepteurs PSI5
(IEC 62228-6:2022)

Integrierte Schaltungen - EMV-Bewertung von Transceivern
- Teil 6: PSI5-Transceiver
(IEC 62228-6:2022)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

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The following dates are fixed:

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Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61967-1	-	Integrated circuits - Measurement of electromagnetic emissions - Part 1: General conditions and definitions	EN IEC 61967-1	-
IEC 61967-4	-	Integrated circuits - Measurement of electromagnetic emissions - Part 4: Measurement of conducted emissions - 1 ohm/150 ohm direct coupling method	EN IEC 61967-4	-
IEC 62132-1	-	Integrated circuits - Measurement of electromagnetic immunity - Part 1: General conditions and definitions	EN 62132-1	-
IEC 62132-4	-	Integrated circuits - Measurement of electromagnetic immunity 150 kHz to 1 GHz - Part 4: Direct RF power injection method	EN 62132-4	-
IEC 62215-3	-	Integrated circuits - Measurement of impulse immunity - Part 3: Non-synchronous transient injection method	EN 62215-3	-
IEC 62228-1	-	Integrated circuits - EMC evaluation of transceivers - Part 1: General conditions and definitions	EN IEC 62228-1	-
ISO 7637-2	-	Road vehicles - Electrical disturbances from conduction and coupling - Part 2: Electrical transient conduction along supply lines only	-	-
ISO 10605	-	Road vehicles - Test methods for electrical disturbances from electrostatic discharge	-	-



INTERNATIONAL STANDARD

NORME INTERNATIONALE



**Integrated circuit – EMC evaluation of transceivers –
Part 6: PSI5 transceivers**

**Circuits intégrés – Évaluation de la CEM des émetteurs-récepteurs –
Partie 6: Émetteurs-récepteurs PSI5**

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